

# 2SD1719

## Silicon NPN triple diffusion planar type

For power amplification with high forward current transfer ratio

### ■ Features

- High forward current transfer ratio  $h_{FE}$  which has satisfactory linearity
- High emitter-base voltage (Collector open)  $V_{EBO}$
- N type package enabling direct soldering of the radiating fin to the printed circuit board, etc. of small electronic equipment.

### ■ Absolute Maximum Ratings $T_C = 25^\circ\text{C}$

| Parameter                             | Symbol                   | Rating      | Unit             |
|---------------------------------------|--------------------------|-------------|------------------|
| Collector-base voltage (Emitter open) | $V_{CBO}$                | 100         | V                |
| Collector-emitter voltage (Base open) | $V_{CEO}$                | 60          | V                |
| Emitter-base voltage (Collector open) | $V_{EBO}$                | 15          | V                |
| Collector current                     | $I_C$                    | 6           | A                |
| Peak collector current                | $I_{CP}$                 | 12          | A                |
| Base current                          | $I_B$                    | 3           | A                |
| Collector power dissipation           | $P_C$                    | 40          | W                |
|                                       | $T_a = 25^\circ\text{C}$ | 1.3         |                  |
| Junction temperature                  | $T_j$                    | 150         | $^\circ\text{C}$ |
| Storage temperature                   | $T_{stg}$                | -55 to +150 | $^\circ\text{C}$ |

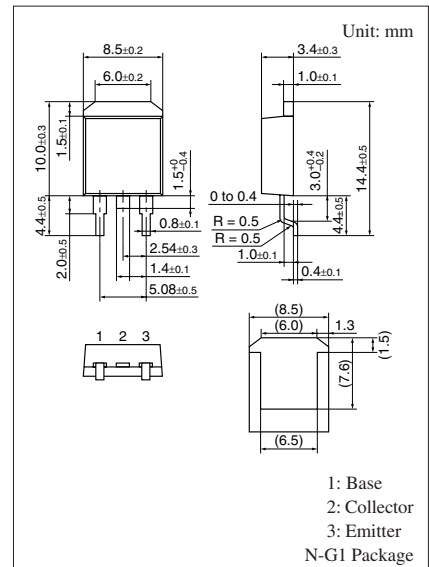
### ■ Electrical Characteristics $T_C = 25^\circ\text{C} \pm 3^\circ\text{C}$

| Parameter                                    | Symbol        | Conditions   | Min | Typ | Max  | Unit          |
|--|---------------|--|-----|-----|------|---------------|
| Collector-emitter voltage (Base open)        | $V_{CEO}$     | $I_C = 25 \text{ mA}, I_B = 0$                                   | 60  |     |      | V             |
| Collector-base cutoff current (Emitter open) | $I_{CBO}$     | $V_{CB} = 100 \text{ V}, I_E = 0$                                |     |     | 100  | $\mu\text{A}$ |
| Emitter-base cutoff current (Collector open) | $I_{EBO}$     | $V_{EB} = 15 \text{ V}, I_C = 0$                                 |     |     | 100  | $\mu\text{A}$ |
| Forward current transfer ratio *             | $h_{FE}$      | $V_{CE} = 4 \text{ V}, I_C = 1 \text{ A}$                        | 300 |     | 2000 | —             |
| Collector-emitter saturation voltage         | $V_{CE(sat)}$ | $I_C = 5 \text{ A}, I_B = 0.1 \text{ A}$                         |     |     | 0.5  | V             |
| Transition frequency                         | $f_T$         | $V_{CE} = 12 \text{ V}, I_C = 0.5 \text{ A}, f = 10 \text{ MHz}$ |     | 30  |      | MHz           |
| Turn-on time                                 | $t_{on}$      | $I_C = 5 \text{ A}$  |     | 0.3 |      | $\mu\text{s}$ |
| Storage time                                 | $t_{stg}$     | $I_{B1} = 0.1 \text{ A}, I_{B2} = -0.1 \text{ A}$                |     | 1.5 |      | $\mu\text{s}$ |
| Fall time                                    | $t_f$         | $V_{CC} = 50 \text{ V}$  |     | 0.6 |      | $\mu\text{s}$ |

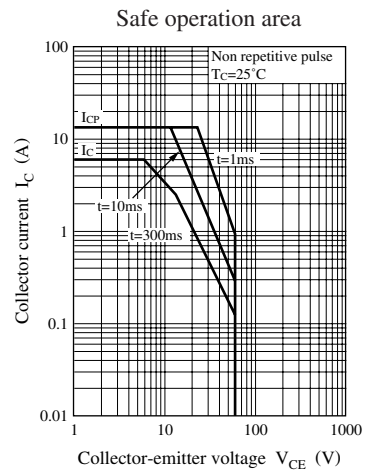
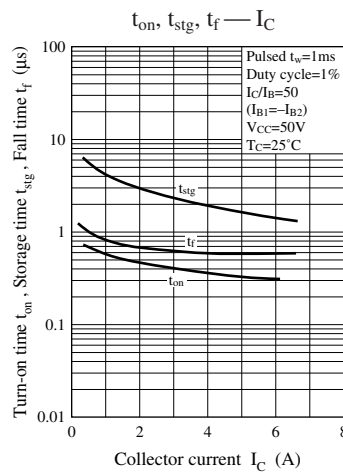
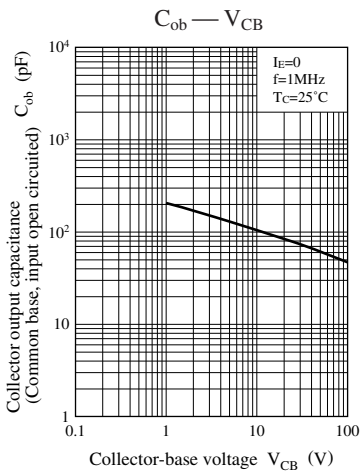
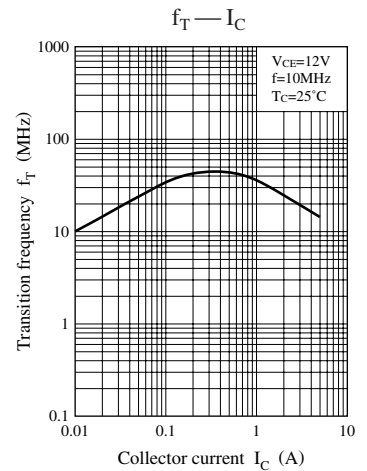
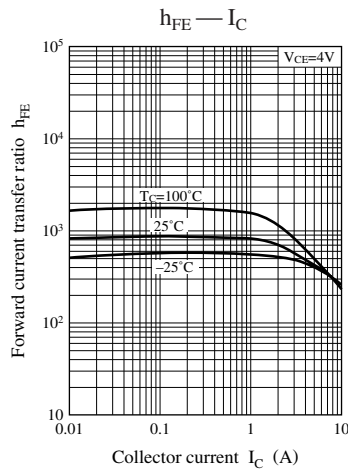
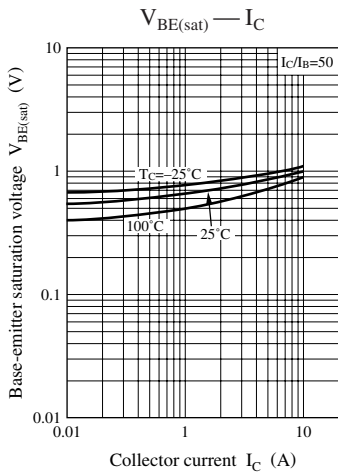
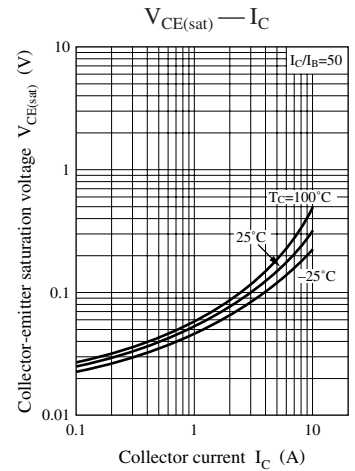
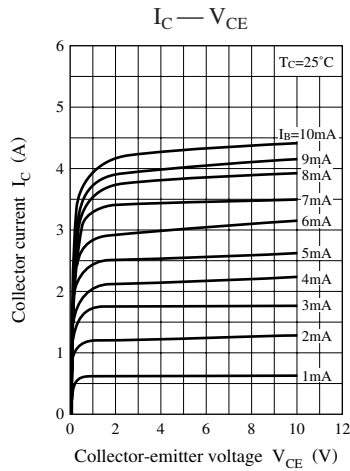
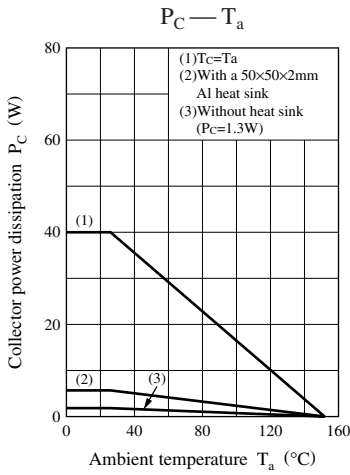
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

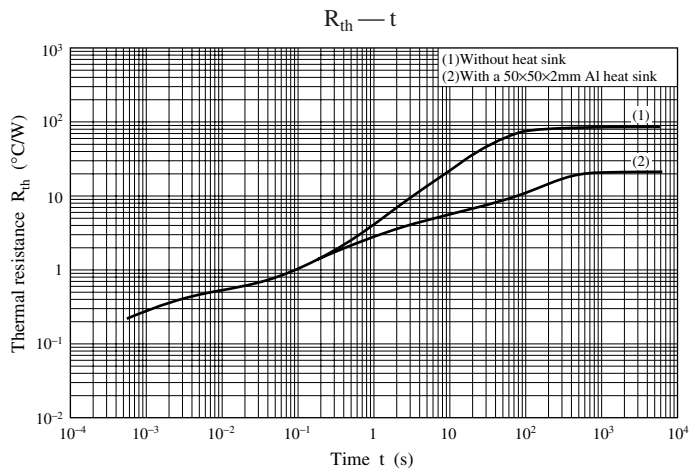
2. \*: Rank classification

| Rank     | Q           | P           |
|----------|-------------|-------------|
| $h_{FE}$ | 300 to 1200 | 800 to 2000 |



Note) Self-supported type package is also prepared.





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